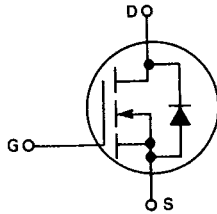
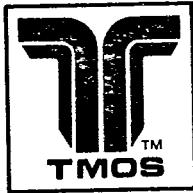


IRF530
IRF531
IRF532
IRF533

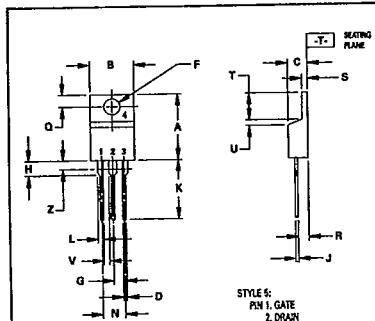
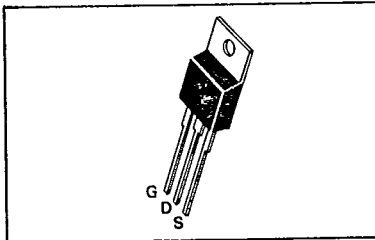
**N-CHANNEL ENHANCEMENT-MODE SILICON GATE
 TMOS POWER FIELD EFFECT TRANSISTOR**

These TMOS Power FETs are designed for low voltage, high speed power switching applications such as switching regulators, converters, solenoid and relay drivers.

- Silicon Gate for Fast Switching Speeds
- Rugged — SOA is Power Dissipation Limited
- Source-to-Drain Diode Characterized for Use With Inductive Loads



Part Number	V _{DS}	r _{DS(on)}	I _D
IRF530	100 V	0.18 Ω	14 A
IRF531	60 V	0.18 Ω	14 A
IRF532	100 V	0.25 Ω	12 A
IRF533	60 V	0.25 Ω	12 A



MAXIMUM RATINGS

Rating	Symbol	IRF				Unit
		530	531	532	533	
Drain-Source Voltage	V _{DSS}	100	60	100	60	Vdc
Drain-Gate Voltage (R _{GS} = 1.0 MΩ)	V _{DGR}	100	60	100	60	Vdc
Gate-Source Voltage	V _{GS}	± 20				Vdc
Continuous Drain Current T _C = 25°C	I _D	14	14	12	12	Adc
Continuous Drain Current T _C = 100°C	I _D	9.0	9.0	8.0	8.0	Adc
Drain Current — Pulsed	I _{DM}	56	56	48	48	Adc
Total Power Dissipation @ T _C = 25°C Derate above 25°C	P _D	75 0.6				Watts W/°C
Operating and Storage Temperature Range	T _J , T _{stg}	-55 to 150				°C

THERMAL CHARACTERISTICS

Thermal Resistance Junction to Case	R _{θJC}	1.67	°C/W
Junction to Ambient	R _{θJA}	62.5	°C/W
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	T _L	300	°C

See the MTM12N10 Designer's Data Sheet for a complete set of design curves for this product.

- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION INCH.
 3. DIM Z DEFINES A ZONE WHERE ALL BODY AND LEAD IRREGULARITIES ARE ALLOWED.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	14.48	15.75	0.570	0.620
B	3.66	13.78	0.280	0.465
C	4.67	4.82	0.180	0.190
D	0.64	0.98	0.025	0.039
F	3.61	3.71	0.142	0.147
G	2.42	2.68	0.096	0.106
H	2.80	3.83	0.110	0.151
J	0.26	0.55	0.014	0.022
K	12.75	14.27	0.500	0.562
L	1.15	1.29	0.045	0.051
N	4.83	5.33	0.190	0.210
O	2.54	3.04	0.100	0.120
R	2.04	2.29	0.080	0.110
S	1.15	1.29	0.045	0.051
T	5.97	6.47	0.235	0.255
U	0.00	1.27	0.000	0.050
V	1.15	—	0.045	—
Z	—	2.04	—	0.080

**CASE 221A-04
 TO-220AB**

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

14E D

Characteristic	Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS					
Drain-Source Breakdown Voltage (V _{GS} = 0, I _D = 250 μA)	V _{(BR)DSS}	100 60	—	—	V _{dc}
Zero Gate Voltage Drain Current (V _{GS} = 0 V, V _{DS} = Rated V _{DSS}) (V _{GS} = 0 V, V _{DS} = 0.8 Rated V _{DSS} , T _C = 125°C)	I _{DSS}	—	—	0.25 1.0	mAdc
Forward Gate-Body Leakage Current (V _{GS} = 20 V, V _{DS} = 0)	I _{GSSF}	—	—	100	nAdc
Reverse Gate-Body Leakage Current (V _{GS} = -20 V, V _{DS} = 0)	I _{GSSR}	—	—	-100	nAdc
ON CHARACTERISTICS*					
Gate Threshold Voltage (V _{DS} = V _{GS} , I _D = 250 μA)	V _{GS(th)}	2.0	—	4.0	V _{dc}
On-State Drain Current (V _{DS} = 25 V, V _{GS} = 10 V)	I _{D(on)}	14 12	—	—	Adc
Static Drain-Source On-Resistance (V _{GS} = 10 V, I _D = 8.0 A)	r _{DS(on)}	—	—	0.18 0.25	Ohm
Forward Transconductance (V _{DS} = 15 V, I _D = 8.0 A)	g _{FS}	4.0	—	—	mhos
DYNAMIC CHARACTERISTICS					
Input Capacitance	C _{iss} C _{oss} C _{rss}	—	—	800	pF
Output Capacitance				500	
Reverse Transfer Capacitance				150	
SWITCHING CHARACTERISTICS* (T_J = 100°C)					
Turn-On Delay Time	V _{DD} = 36 V, I _D = 8.0 A Z _O = 15 Ω	—	—	30	ns
Rise Time				75	
Turn-Off Delay Time				40	
Fall Time				45	
SOURCE DRAIN DIODE CHARACTERISTICS*					
Forward On-Voltage	V _{SD}	—	—	2.3	V _{dc}
Forward Turn-On Time				Limited by stray inductance	
Reverse Recovery Time				360	
INTERNAL PACKAGE INDUCTANCE (TO-220)					
Internal Drain Inductance (Measured from the contact screw on tab to center of die) (Measured from the drain lead 0.25" from package to center of die)	L _d	—	3.5 4.5	—	nH
Internal Source Inductance (Measured from the source lead 0.25" from package to source bond pad.)	L _s	—	7.5	—	

*Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0 %.

FIGURE 1 — SWITCHING TEST CIRCUIT

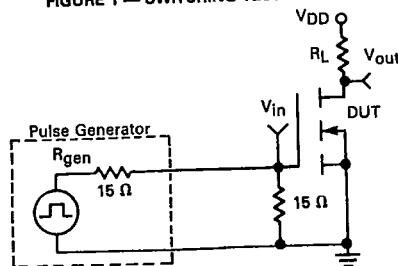


FIGURE 2 — SWITCHING WAVEFORMS

